

Thermal Excitation of Broadband and Long-range Surface Waves on SiO₂ Submicron Films

Sergei Gluchko,¹ Bruno Palpant,² Sebastian Volz,^{1,3} Rémy Braive,⁴ and Thomas Antoni²

¹ *EM2C, CNRS, CentraleSupélec, Grande Voie des Vignes, 92295 Châtenay-Malabry, France*

² *LPQM, CNRS, CentraleSupélec, ENS Cachan, Grande Voie des Vignes, 92290 Châtenay-Malabry, France*

³ *Laboratory for Integrated Micro-Mechatronic Systems, The University of Tokyo, 4-6-1 Komaba, Meguro-ku, Tokyo*

⁴ *Centre de Nanosciences et de Nanotechnologies (C2N), CNRS, Université Paris-Saclay, 91460 Marcoussis, France*

Following previous theoretical works uncovering the possible existence of broad band surface electromagnetic modes in thin films [1, 2], we have measured and calculated the far-field thermal emission of a submicron SiO₂ layer with a diffraction grating deposited itself on a metallic layer from near- to far-infrared frequencies as shown on Fig. 1. Thermally excited Zenneck surface waves, Surface Phonon Polaritons and guided surface waves were detected in the 882 cm⁻¹ to 3725 cm⁻¹ frequency range by means of Fourier transform infrared emission spectroscopy. The dispersion relation and spectral coherence length - found as large as 500 μm - are in good agreement with theoretical and numerical expectations. Optical and thermal applications are envisioned due to the photon-like behavior and the large propagation length of the observed modes. Those waves are indeed likely to open an unknown but very efficient heat channel, which can even predominate over heat conduction [3].

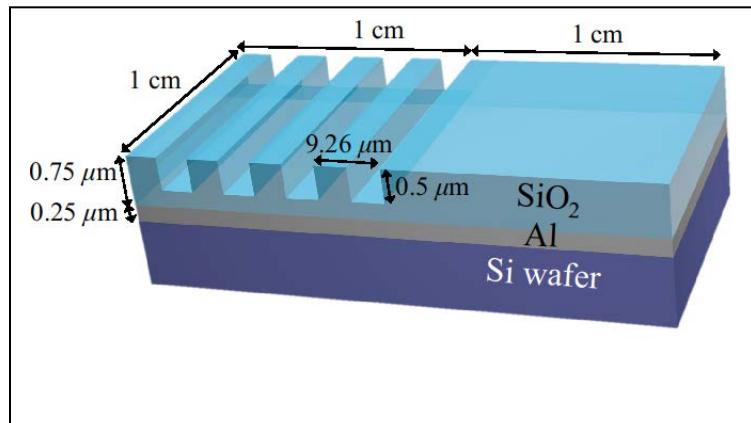


Fig. 1: Sample consisting of a SiO₂ layer deposited on an aluminum layer with a diffraction grating designed to detect thermally excited surface waves in far field.

[1] J. Ordonez-Miranda, L. Tranchant, T. Tokunaga, B. Kim, B Palpant, Y. Chalopin, T. Antoni, and S. Volz *J. Appl. Phys.* **113**, 084311 (2013).

[2] F. Yang, J. R. Sambles, and G. W. Bradberry, *Phys. Rev. B.* **44**, 5855 (1991).

[3] D. A. Chen, A. Narayanaswamy, and G. Chen, *Phys. Rev. B.* **72**, 155435 (2005).